TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC109AP,TC74HC109AF,TC74HC109AFN

Dual J-$\overline{K}$ Flip-Flop with Preset and Clear

The TC74HC109A is a high speed CMOS J-$\overline{K}$ FLIP FLOP fabricated with silicon gate C^2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

In accordance with the logic levels applied to the J and $\overline{K}$ inputs, the outputs change state on the positive going transition of the clock pulse.

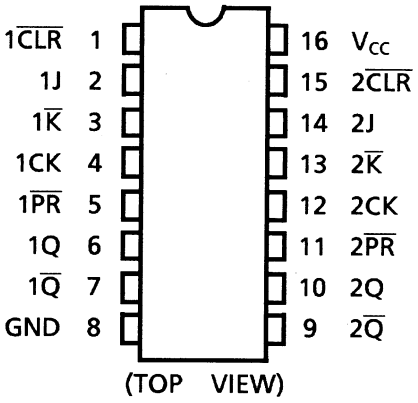
$\overline{CLR}$ and $\overline{PR}$ are independent of the clock and are accomplished by a low logic level on the corresponding input.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

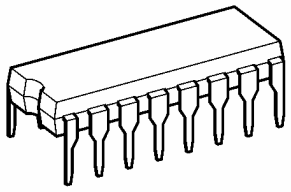
- High speed: f_{max} = 63 MHz (typ.) at V_{CC} = 5 V
- Low power dissipation: I_{CC} = 2 μA (max) at Ta = 25°C
- High noise immunity: $V_{NIH} = V_{NIL}$ = 28% V_{CC} (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: $|I_{OH}| = I_{OL}$ = 4 mA (min)
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~6 V
- Pin and function compatible with 74LS109

Pin Assignment



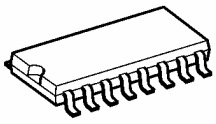
Note: xxxFN (JEDEC SOP) is not available in Japan.

TC74HC109AP



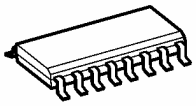
DIP16-P-300-2.54A

TC74HC109AF



SOP16-P-300-1.27A

TC74HC109AFN

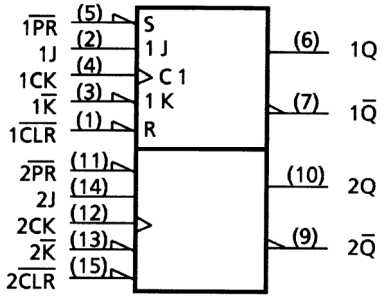


SOL16-P-150-1.27

Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

IEC Logic Symbol

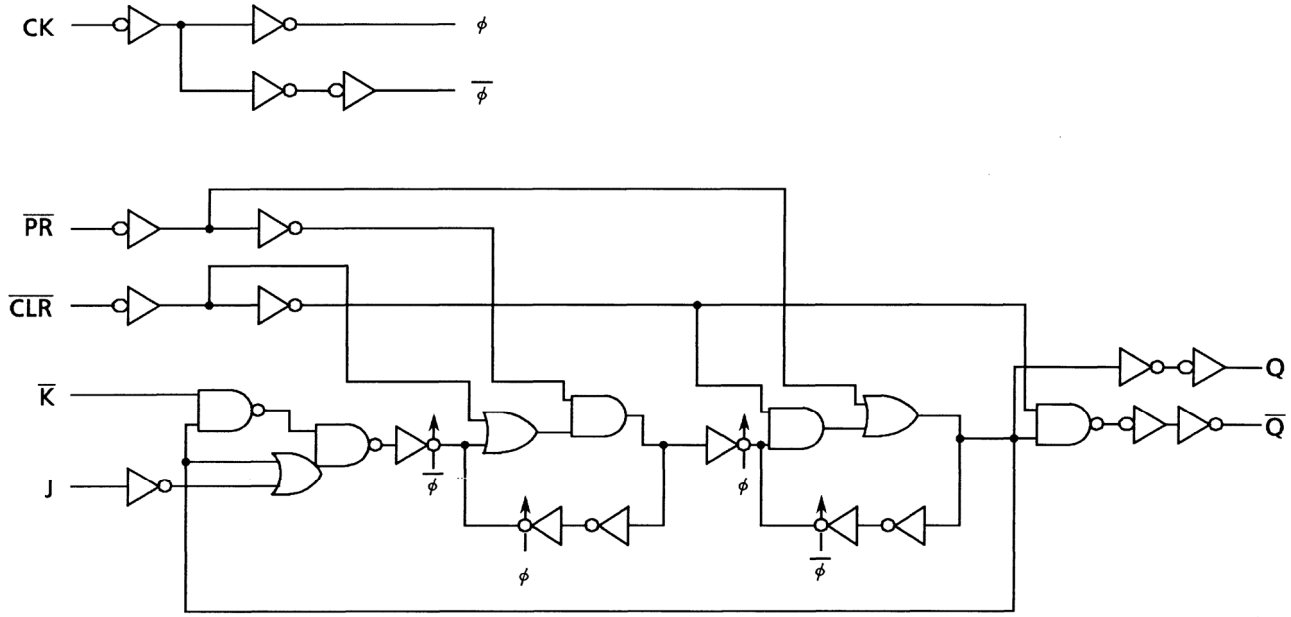


Truth Table

Inputs					Outputs		Function
$\overline{CLR}$	$\overline{PR}$	J	$\overline{K}$	CK	Q	$\overline{Q}$	
L	H	X	X	X	L	H	Clear
H	L	X	X	X	H	L	Preset
L	L	X	X	X	H	H	
H	H	L	H	↑	Q_n	$\overline{Q}_n$	No Change
H	H	L	L	↑	L	H	
H	H	H	H	↑	H	L	
H	H	H	L	↑	$\overline{Q}_n$	Q_n	Toggle
H	H	X	X	↓	Q_n	$\overline{Q}_n$	No Change

X: Don't care

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	−0.5~7	V
DC input voltage	V_{IN}	−0.5~V_{CC} + 0.5	V
DC output voltage	V_{OUT}	−0.5~V_{CC} + 0.5	V
Input diode current	I_{IK}	±20	mA
Output diode current	I_{OK}	±20	mA
DC output current	I_{OUT}	±25	mA
DC V_{CC}/ground current	I_{CC}	±50	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	−65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook (“Handling Precautions”/“Derating Concept and Methods”) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = −40°C~65°C. From Ta = 65°C to 85°C a derating factor of −10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2~6	V
Input voltage	V_{IN}	0~V_{CC}	V
Output voltage	V_{OUT}	0~V_{CC}	V
Operating temperature	T_{opr}	−40~85	°C
Input rise and fall time	t_r, t_f	0~1000 (V_{CC} = 2.0 V) 0~500 (V_{CC} = 4.5 V) 0~400 (V_{CC} = 6.0 V)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		V_{CC} (V)	Ta = 25°C Min	Ta = 25°C Typ.	Ta = 25°C Max	Ta = −40~85°C Min	Ta = −40~85°C Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	—	1.50	—	V
				4.5	3.15	—	—	3.15	—	
				6.0	4.20	—	—	4.20	—	
Low-level input voltage	V_{IL}	—		2.0	—	—	0.50	—	0.50	V
				4.5	—	—	1.35	—	1.35	
				6.0	—	—	1.80	—	1.80	
High-level output voltage	V_{OH}	V_{IN} = V_{IH} or V_{IL}	I_{OH} = −20 μA	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
				6.0	5.9	6.0	—	5.9	—	
			I_{OH} = −4 mA	4.5	4.18	4.31	—	4.13	—	
			I_{OH} = −5.2 mA	6.0	5.68	5.80	—	5.63	—	
Low-level output voltage	V_{OL}	V_{IN} = V_{IH} or V_{IL}	I_{OL} = 20 μA	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
				6.0	—	0.0	0.1	—	0.1	
			I_{OL} = 4 mA	4.5	—	0.17	0.26	—	0.33	
			I_{OL} = 5.2 mA	6.0	—	0.18	0.26	—	0.33	
Input leakage current	I_{IN}	V_{IN} = V_{CC} or GND		6.0	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I_{CC}	V_{IN} = V_{CC} or GND		6.0	—	—	2.0	—	20.0	μA

Timing Requirements (input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	Ta = 25°C			Ta = −40 ~85°C	Unit
			V_{CC} (V)	Typ.	Limit	Limit	
Minimum pulse width (CK)	$t_{W(L)}$ $t_{W(H)}$	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum pulse width ($\overline{PR}$, $\overline{CLR}$)	$t_{W(L)}$	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum set-up time	t_s	—	2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum hold time	t_h	—	2.0	—	0	0	ns
			4.5	—	0	0	
			6.0	—	0	0	
Minimum removal time ($\overline{PR}$, $\overline{CLR}$)	t_{rem}	—	2.0	—	50	65	ns
			4.5	—	10	13	
			6.0	—	9	11	
Clock frequency	f	—	2.0	—	6	5	MHz
			4.5	—	31	25	
			6.0	—	36	29	

AC Characteristics ($C_L = 15$ pF, $V_{CC} = 5$ V, Ta = 25°C, input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	t_{TLH} t_{THL}	—	—	6	12	ns
Propagation delay time (CK-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	—	13	26	ns
Propagation delay time ($\overline{PR}$, $\overline{CLR}$-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	—	13	26	ns
Maximum clock frequency	f_{max}	—	33	63	—	MHz

AC Characteristics (C_L = 50 pF, input: $t_r = t_f$ = 6 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = −40~85°C		Unit
			V_{CC} (V)	Min	Typ.	Max	Min	Max	
Output transition time	t_{TLH} t_{THL}	—	2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation delay time (CK-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	2.0	—	50	150	—	190	ns
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
Propagation delay time ($\overline{PR}$, $\overline{CLR}$-Q, $\overline{Q}$)	t_{pLH} t_{pHL}	—	2.0	—	50	150	—	190	ns
			4.5	—	16	30	—	38	
			6.0	—	13	26	—	32	
Maximum clock frequency	f_{max}	—	2.0	6	17	—	5	—	MHz
			4.5	31	59	—	25	—	
			6.0	36	67	—	29	—	
Input capacitance	C_{IN}	—		—	5	10	—	10	pF
Power dissipation capacitance	C_{PD} (Note)	—		—	41	—	—	—	pF

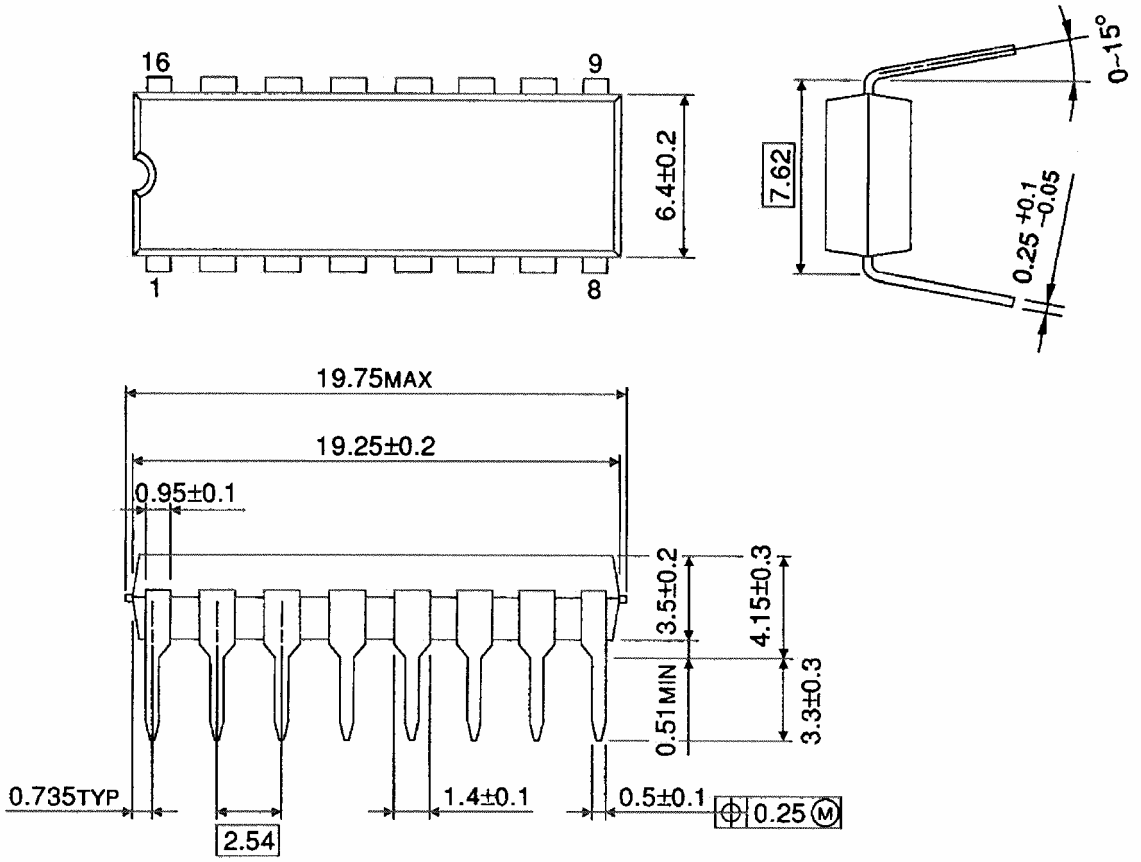
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}\ (opr) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2\ (per\ F/F)$$

Package Dimensions

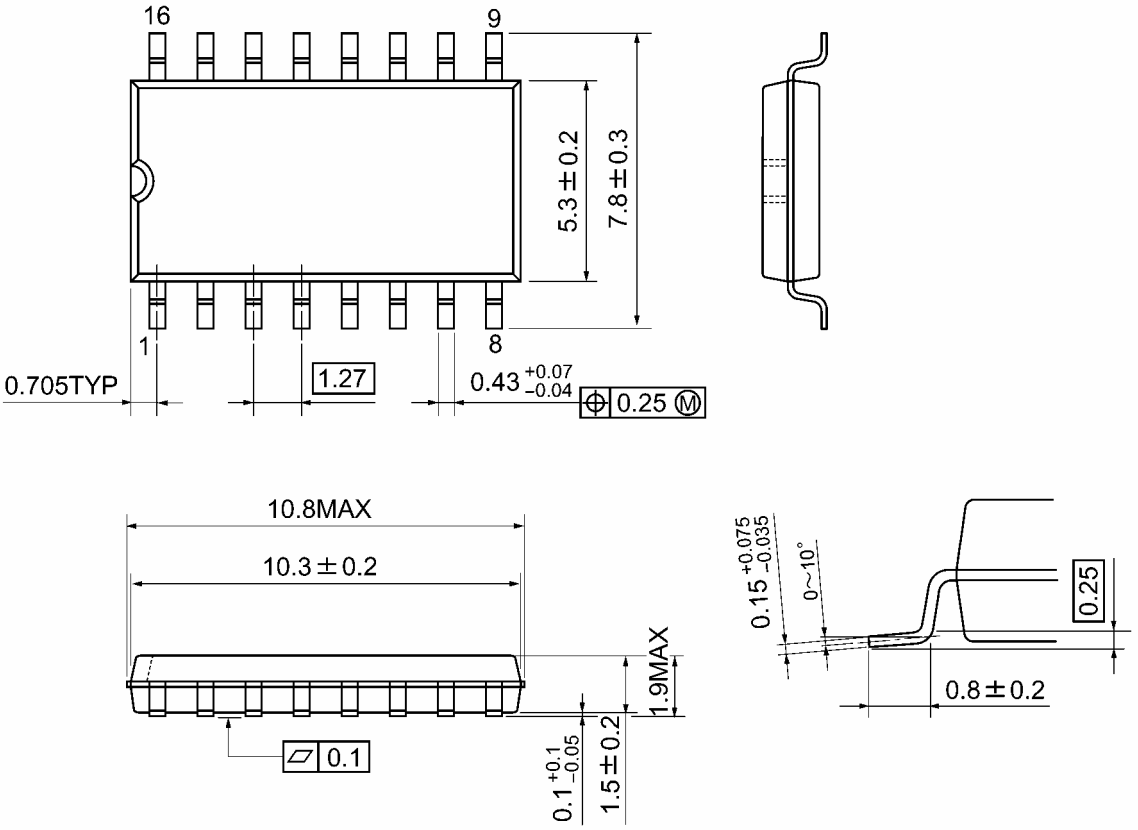
DIP16-P-300-2.54A Unit : mm



Weight: 1.00 g (typ.)

Package Dimensions

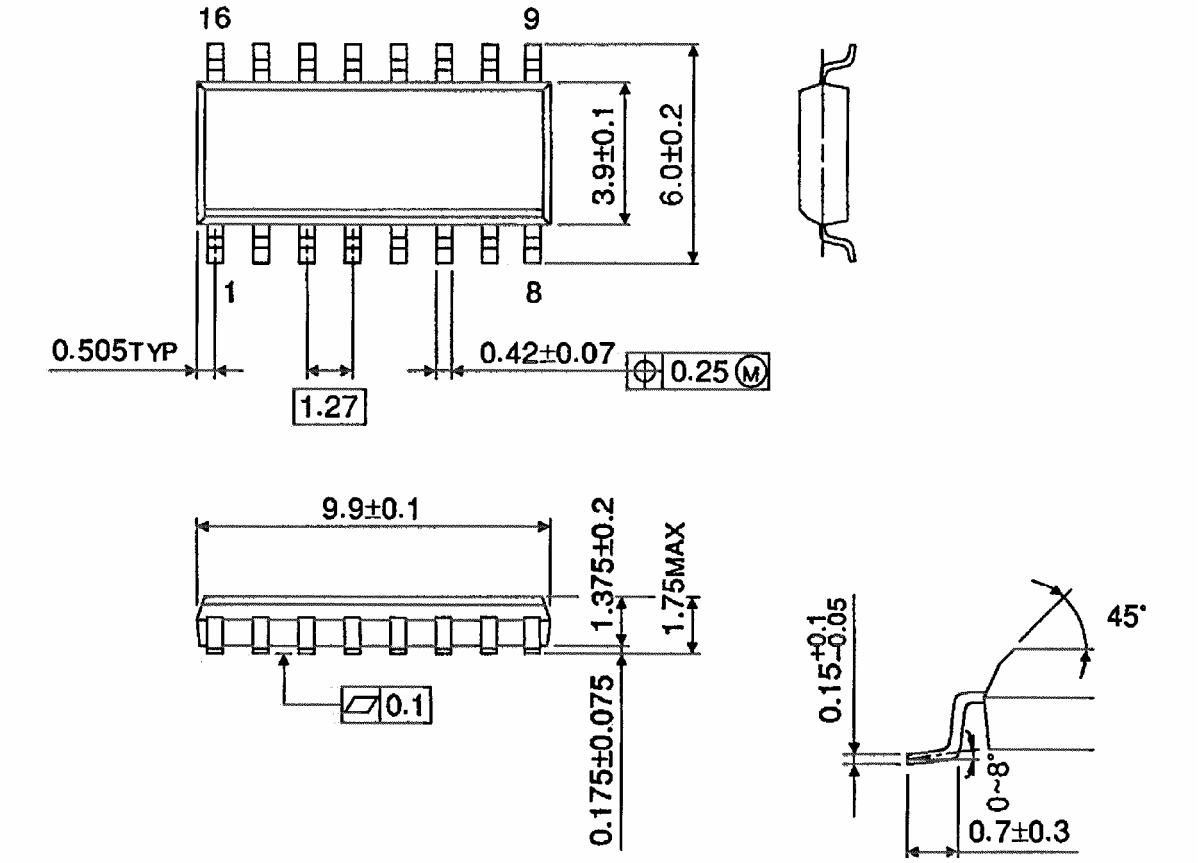
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27 Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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